

Abstracts

RF Reliability Testing of L-Band Power Transistors (Abstract)

W. Weisenberger, B.C. Dodson, Jr. and A. Christou. "RF Reliability Testing of L-Band Power Transistors (Abstract)." 1974 S-MTT International Microwave Symposium Digest of Technical Papers 74.1 (1974 [MWSYM]): 138-138.

Accelerated life tests using pulsed rf power conditions have been incorporated in order to evaluate the reliability of L-band power transistors for use in phased array radar programs. The basic philosophies, test procedures, and diagnostic techniques used will be explained and an explanation of how to use the data will be given.

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